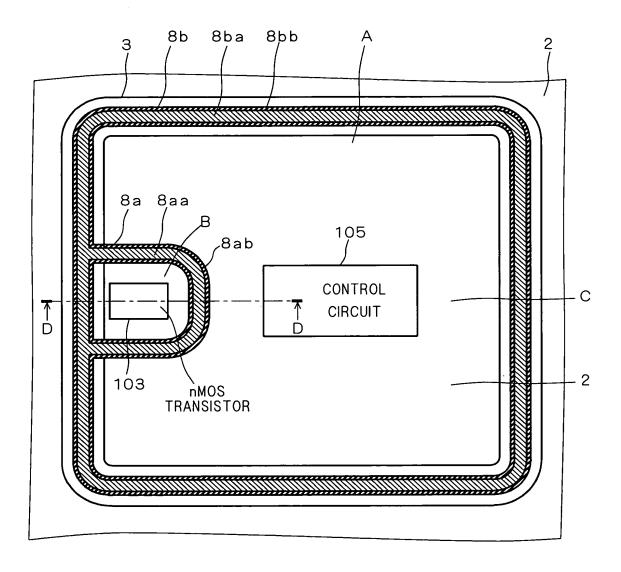
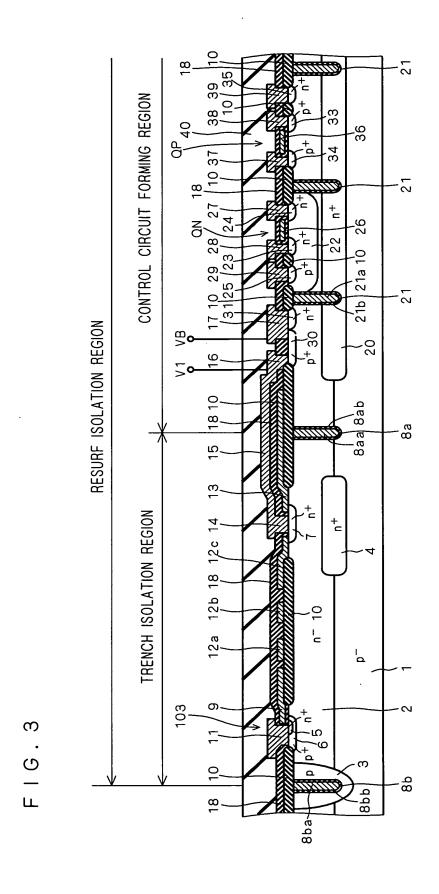


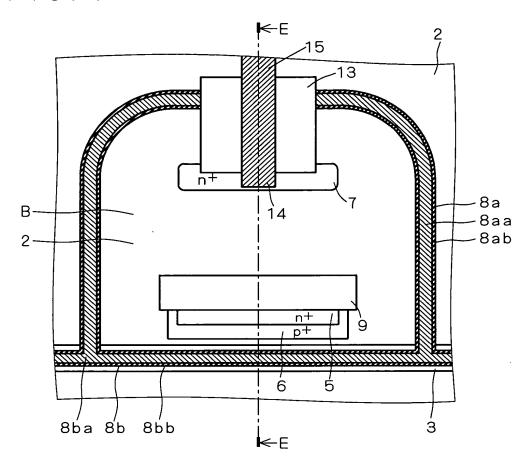
F I G. 1

F I G . 2





F | G . 4



F I G . 5

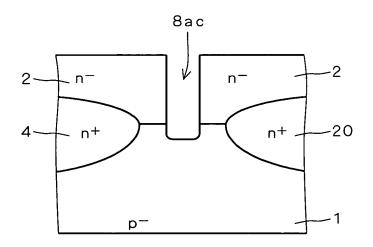
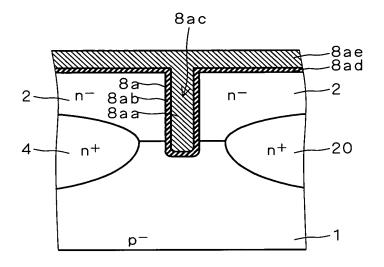
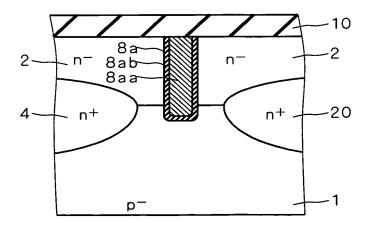


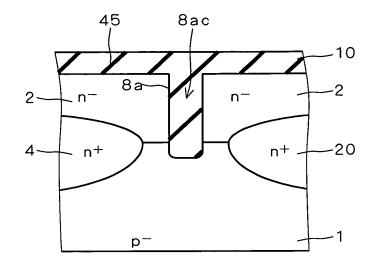
FIG.6



F | G . 7



F I G . 8



F I G . 9

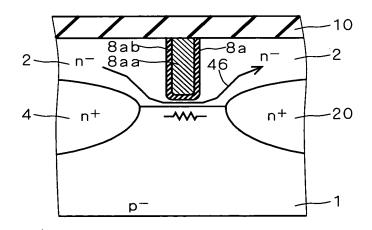
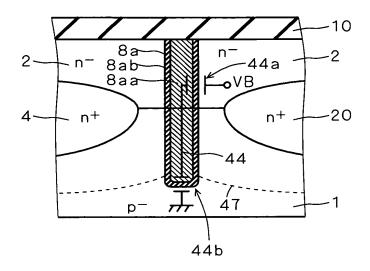
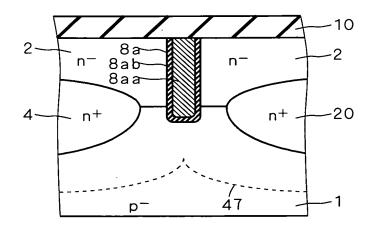
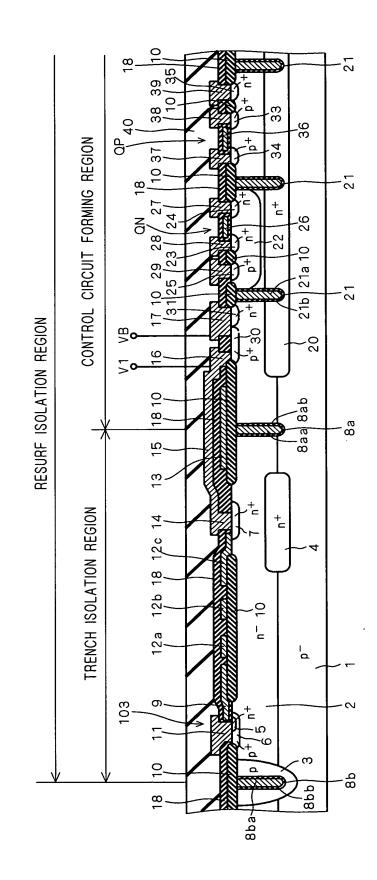


FIG. 10



F I G . 11

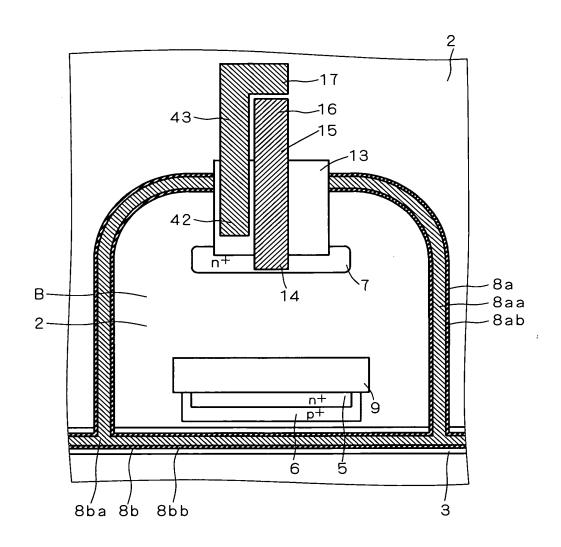


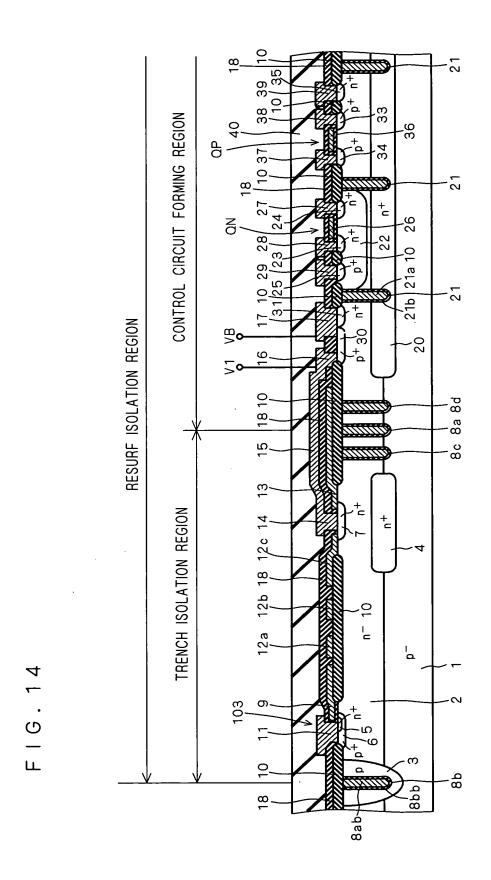


F I G . 1

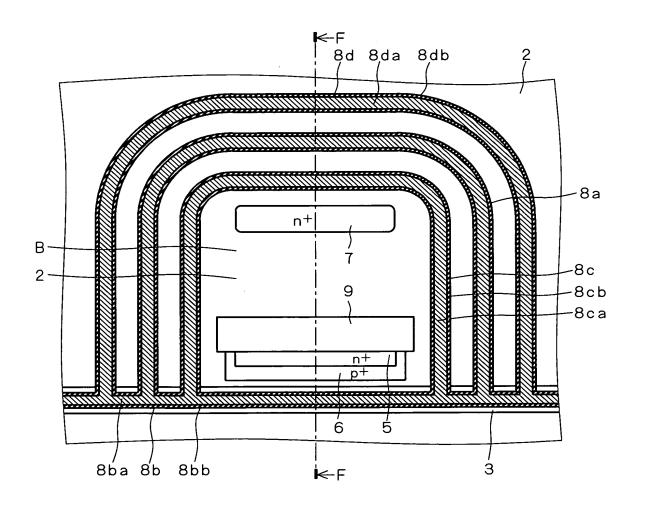
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F I G . 13

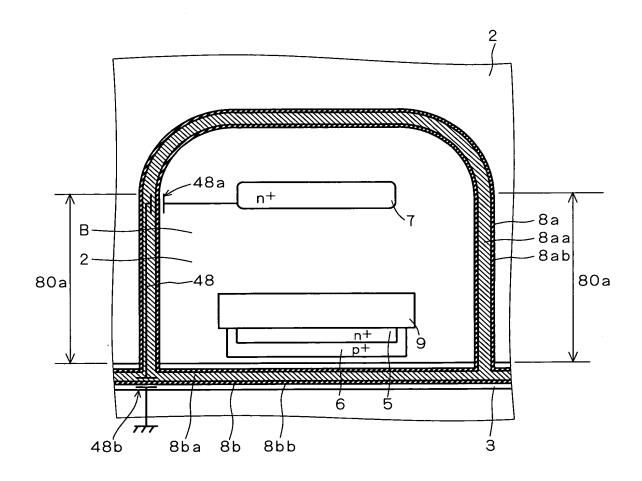




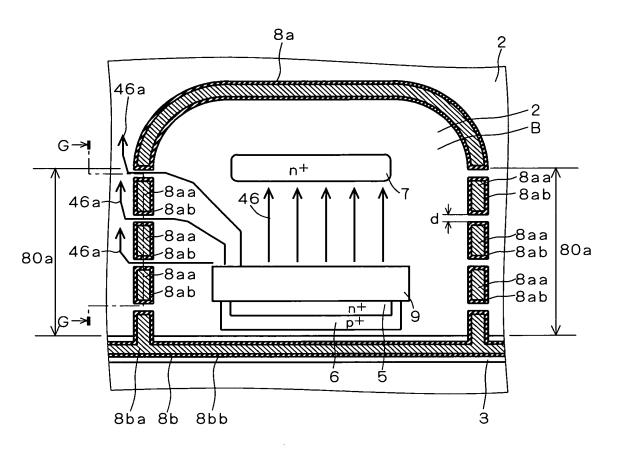
F I G . 15



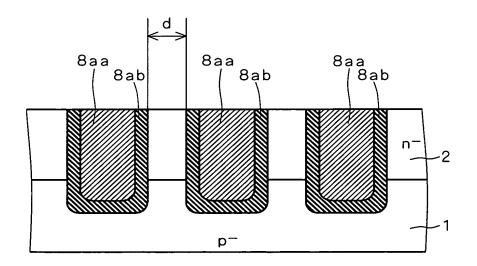
F | G. 16

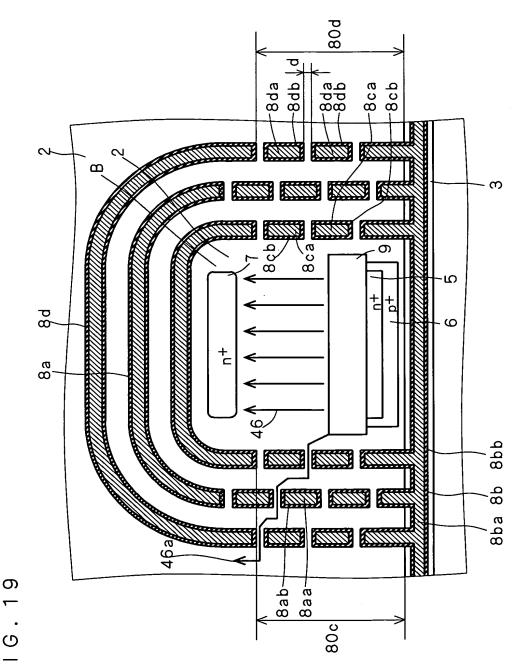


F I G . 17



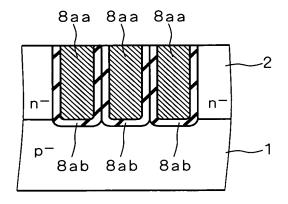
F I G . 18



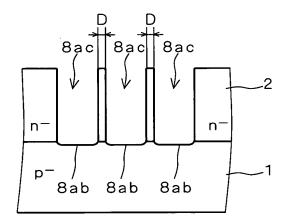


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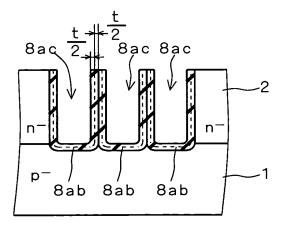
FIG. 20



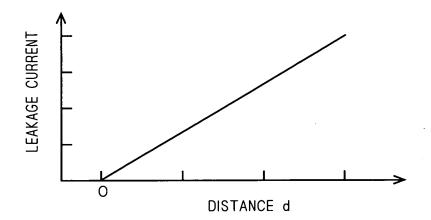
F I G . 2 1



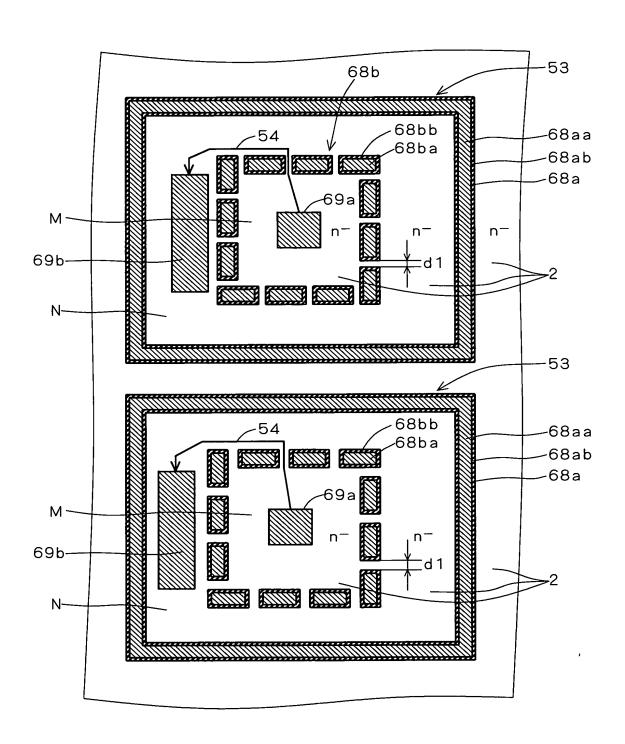
F I G . 22



F I G . 23



F I G . 24



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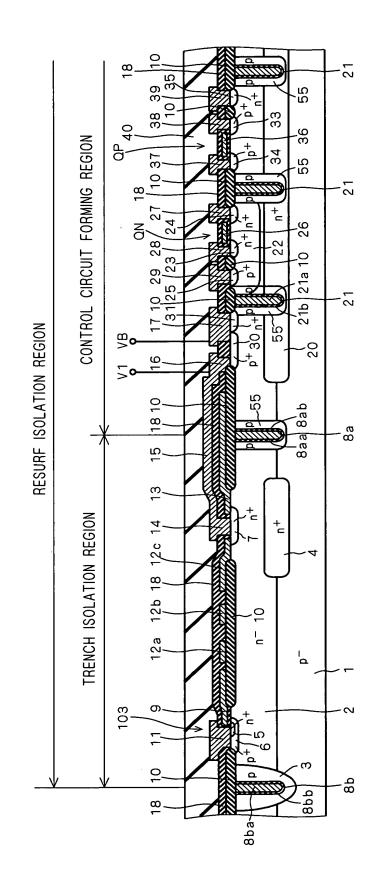
FIG. 25

MEASURE LEAKAGE CURRENT IN EACH ONE OF A PLURALITY OF TEST STRUCTURES 54

EVALUATE MANUFACTURING PROCESS OF IN-LINE PORTION 80a
OF TRENCH ISOLATION STRUCTURE 8a USING LEAKAGE
CURRENT MEASURED IN STEP s1

-s2

___s 1



F1G.2

9

FIG. 27

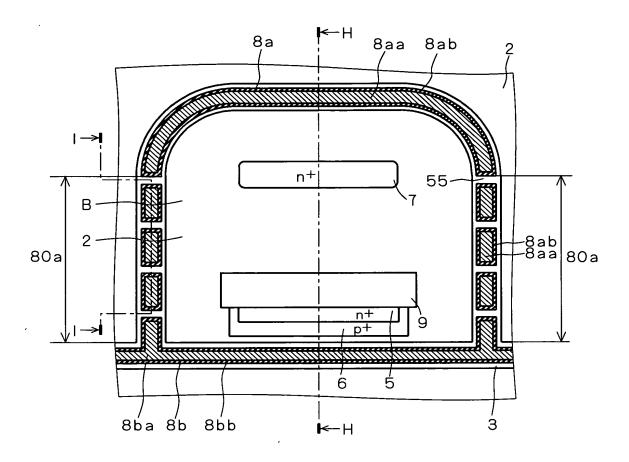
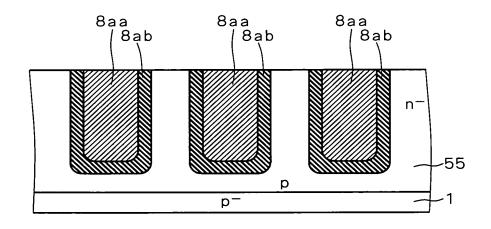
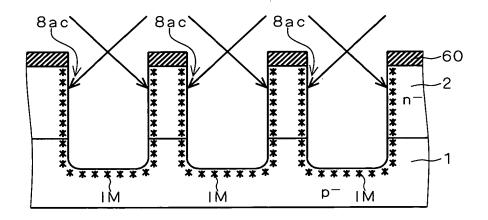


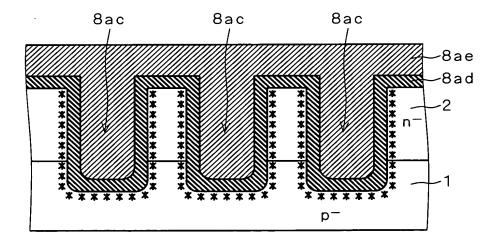
FIG. 28



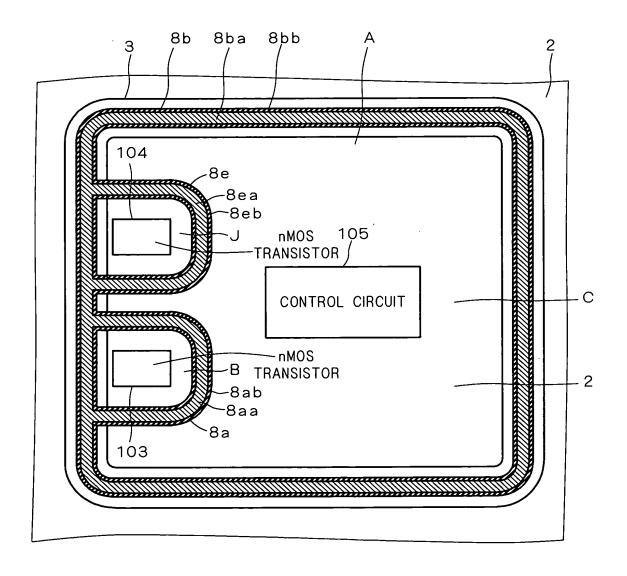
F I G . 29

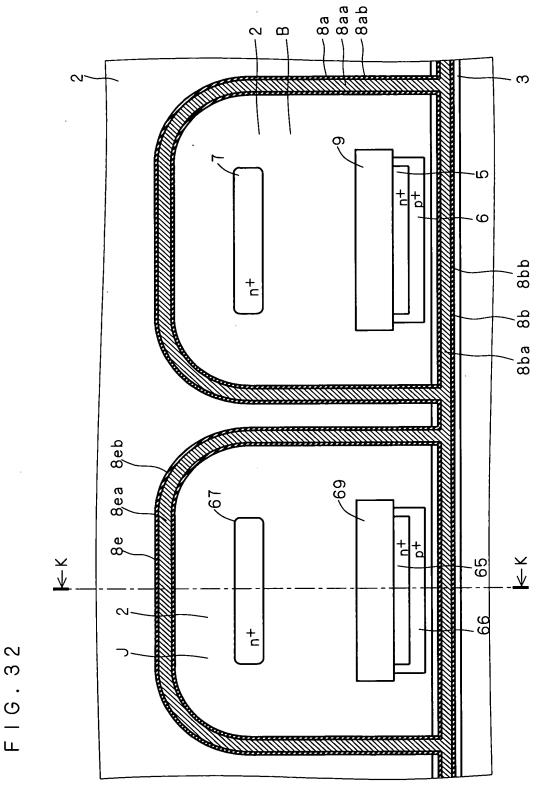


F1G.30



F I G . 31





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FIG. 33

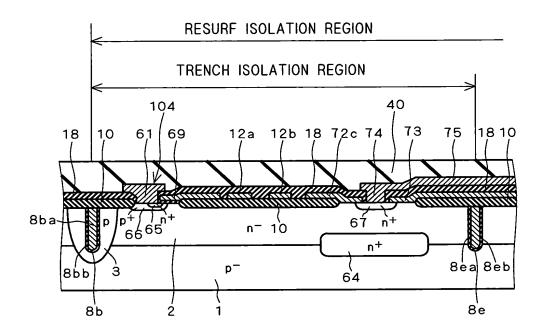


FIG. 34

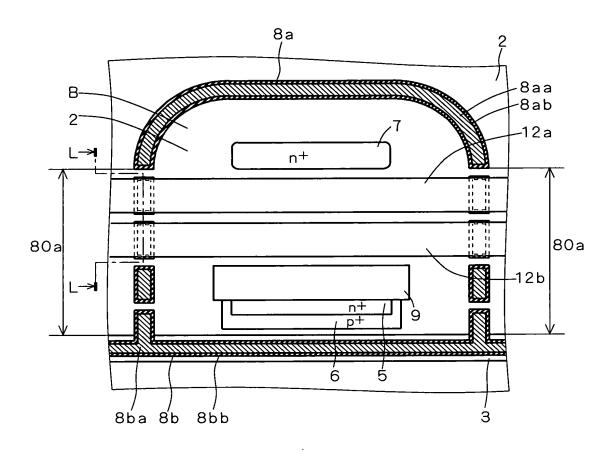


FIG. 35

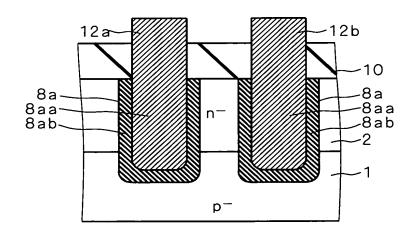


FIG.36

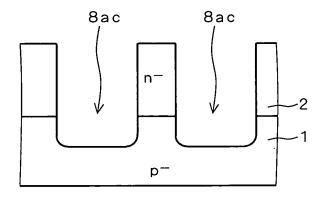
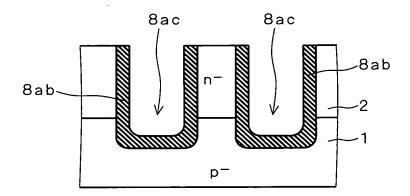


FIG. 37



F I G . 38

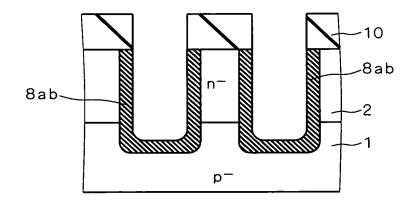
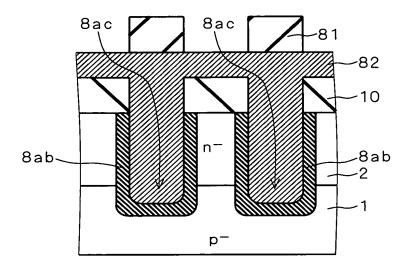


FIG.39



F I G . 40

